Appl. No. 10/708,276
Amdt. dated March 07, 2007
Reply to Office action of February 21, 2007

Amendments to the Claims

Claims 1 – 3, 6 – 12, and 14 – 15 are currently amended. Claims 4 – 5 and 13 are original. No new matter is added by these amendments. Consideration of all amendments is respectfully requested.

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Listing of Claims

Claim 1 (currently amended): A method for determining the integrity of a memory under a plurality of operating environments comprising:

setting a plurality of operating environments respectively corresponding to

10   variations in for a condition to be tested;

repeatedly testing the same memory under each of the plurality of operating environments, respectively;

recording a result of the testing step for each of the plurality of operating environments; and

15   comparing the recorded results for each of the plurality of operating environments, wherein if the results are the same for each of the plurality of operating environments then the memory is determined to have integrity.

20   Claim 2 (currently amended): The method of claim 1 wherein the testing step further comprises:

performing a built-in self test (BIST) on the memory under each of the plurality of operating environments.

25   Claim 3 (currently amended): The method of claim 2 further comprising:

marking a status record memory according to the BIST, wherein the status record memory corresponds to the memory; and

recording the content of the status record memory for each of the plurality of

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operating environments.

Claim 4 (original): The method in claim 1 wherein the condition to be tested is a
variance in supply voltage.

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Claim 5 (original): The method in claim 1 wherein the condition to be tested is a
variance in temperature.

Claim 6 (currently amended): The method of claim 1 wherein the testing step further

10   comprises:
detecting information concerning defects in the memory; and
counting the number of defects in the memory under each of the plurality of
operating environments.

15   Claim 7 (currently amended): The method in claim 6 wherein the recording step
further comprises:
recording storing the number of defects detected in the memory.

Claim 8 (currently amended): The method in claim 7 wherein the comparing step

20   further comprises:
accessing the stored number of defects to determine determining if the
numbers of defects detected in the memory under each of corresponding
to the plurality of operating environments are equal to one another;
wherein if the numbers of defects detected in the memory under each of the

25   plurality of operating environments are equal to one another then the
memory can be determined to have integrity.

Claim 9 (currently amended): The method in claim 6 wherein the recording step
further comprises:

30   recording and storing the position of each defect detected in the memory

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<u>under each of the plurality of operating environments</u>.

Claim 10 (currently amended): The method in claim 9 wherein the comparing step
further comprises:

5   determining if the positions of defects <u>of the memory under each of</u>
~~corresponding to~~ the plurality of operating environments are the same
as one another.

Claim 11 (currently amended): A method for determining the integrity of a memory,

10   comprising:
testing the memory under a first operating environment <u>corresponding to a</u>
<u>condition to be tested</u>;
recording a first result of the testing step under the first operating
environment;

15   testing the memory under a second operating environment, <u>wherein the</u>
<u>second operating environment corresponds to a variation of the</u>
<u>condition to be tested in the first operating environment</u>;
recording a second result of the testing step under the second operating
environment; and

20   comparing the first result with the second result, <u>wherein if the first result is</u>
<u>equal to the second result then the memory is determined to have</u>
<u>integrity</u>.

Claim 12 (currently amended): The method of claim 11 wherein the testing steps

25   further <u>comprise</u> ~~comprises~~:
performing a built-in self test (BIST) on the memory.

Claim 13 (original): The method of claim 12 further comprising:
marking a status record memory according to the BIST, wherein the status

30   record memory corresponds to the memory; and

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recording the content of the status record memory for the current operating
environment.

Claim 14 (currently amended): The method in claim 11 wherein the ~~difference of the~~
5   condition to be tested in the first and the second operating environment ~~lies~~
~~in~~-is supply voltage.

Claim 15 (currently amended): The method in claim 11 wherein the ~~difference of the~~
condition to be tested in the first and the second operating environment ~~lies~~
10   ~~in~~-is temperature.

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